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FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE PE			ATTY DOCKET NO. 862.C2183	A GCATION NO. 09/819,737					
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	· · · · · · · · · · · · · · · · · · ·	OTHER DOCUMENT(S)	(Including Author, Title, Date, Pertiner	nt Pages, Etc.)	_				
and			on Microscope", A.D. Fein July/August 1992, 611-616.		Journal of Va	acuum Science			
	"High Aspect Ratio Aligned Multilayer Microstructure Fabrication", K. Y. Lee, et al., Journal of Vacuum Science and Technology B, Vol. 12, No. 6, November/December 1994, pp. 3425-3430.								
	"Arrayed Miniature Electron Beam Columns For High Throughput Sub-100 nm Lithography", T. H. P. Chang, et al., Journal of Vacuum Science and Technology B, Vol. 10, No. 6, November/December 1992, pp. 2743-2748.								
	"Microstructures for Particle Beam Control", G. W. Jones, et al., Journal of Vacuum Science and Technology B, Vol. 6, No. 6, November/December 1988, pp. 2023-2027.								
	"A Multibeam Scheme for Electron-Beam Lithography", T. Sasaki, Journal of Vacuum Science and Technology, Vol. 19, No. 4, November/December 1981, pp. 963-965.								
EXAMINER	Lu III.	Jana (1)	DATE CONSIDERED (	6-19-0	72				

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered.

Sheet 2 of 2

Include copy of this form with next communication to applicant. SEWVmj

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		_	5,834,783	11/10/1998	Muraki, et al.	250	398			
1			5,864,142	01/26/1999	Muraki, et al.	250	491.1			
			5,905,267	05/18/1999	Muraki	250	492.22			
			5,981,954	11/09/1999	Muraki	250	397			
			6,107,636	08/22/2000	Muraki	250	492.2			
			6,104,035	08/15/2000	Muraki	250	492.22			
			6,166,387	12/26/2000	Muraki, et al.	250	492.2			
			5,929,454	07/27/1999	Muraki, et al.	250	491.1			
			5,939,725	08/17/1999	Muraki	250	492.22			
_			5,973,332	10/26/1999	Muraki, et al.	250	492.2			
			6,137,113	10/24/2000	Muraki	250	492.22			
<u></u>	K	)	4,419,580	12/06/1983	Walker, et al.	250	396 R			
	V			FC	DREIGN PATENT DOCUMENTS					
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